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Introduction

- Ferroelectrics with large piezoelectric and dielectric response are important for numerous applications:
 - Multilayer ceramic capacitors
 - Actuators and high-precision micropositioners
 - Environmental energy harvesters
 - Random access memories¹
- Piezoelectric ultrasound transducers and probes² are instrumental in:
 - Non-destructive structural evaluation
 - Monitoring of light water nuclear power plants
 - Monitoring of conditions in spent fuel repositories²
 - Advanced reactor designs³
- Especially of interest are autonomous microsystems operating in locations with high radiation exposure.

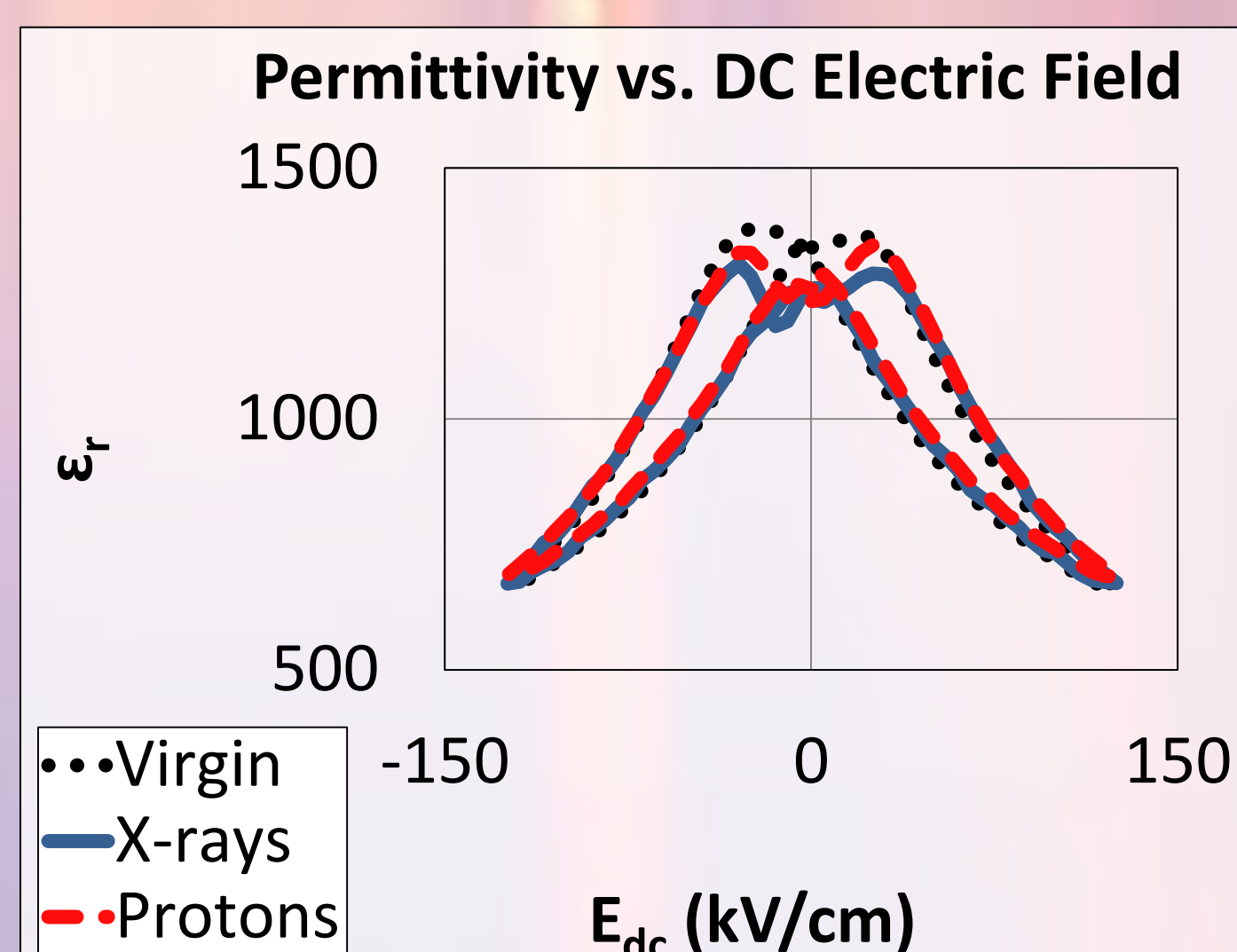
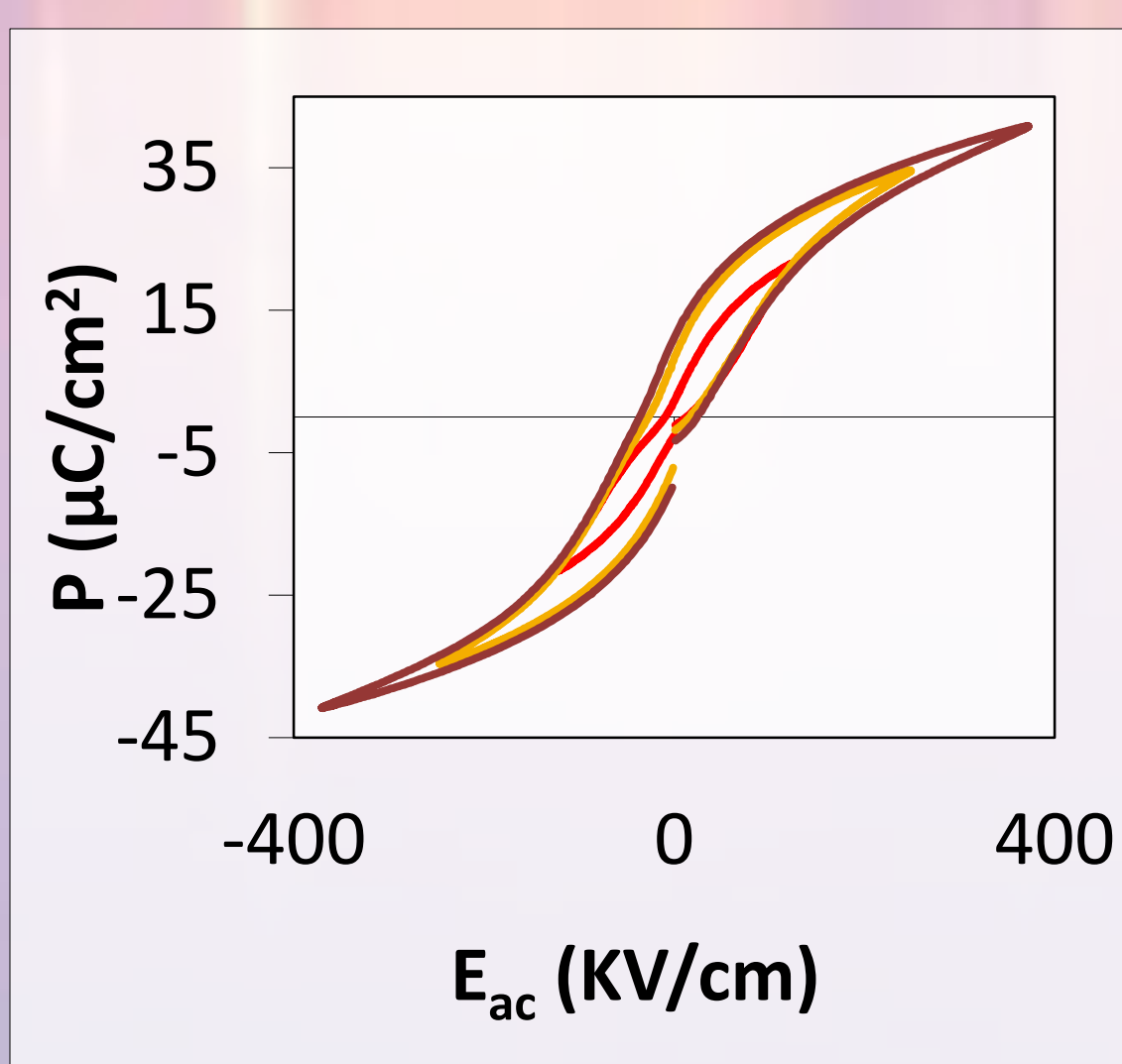
Research Objective: Investigate effects of irradiation on the dielectric and piezoelectric response of

- Pb(Mg_{1/3}Nb_{2/3})O₃-PbTiO₃ (PMN-PT)
- [001] [011] and [111] orientation
- 0.5 mm thick

single crystals as a function of irradiation source and energy.

Background

- Previous study on Pb(Zr_xTi_{1-x})O₃ (PZT) thin films showed up to a 20% radiation induced piezoelectric response degradation.
- Characterization suggests a reduction of the extrinsic contributions to the response by the increased pinning of the domain walls by radiation-induced point defects.⁴



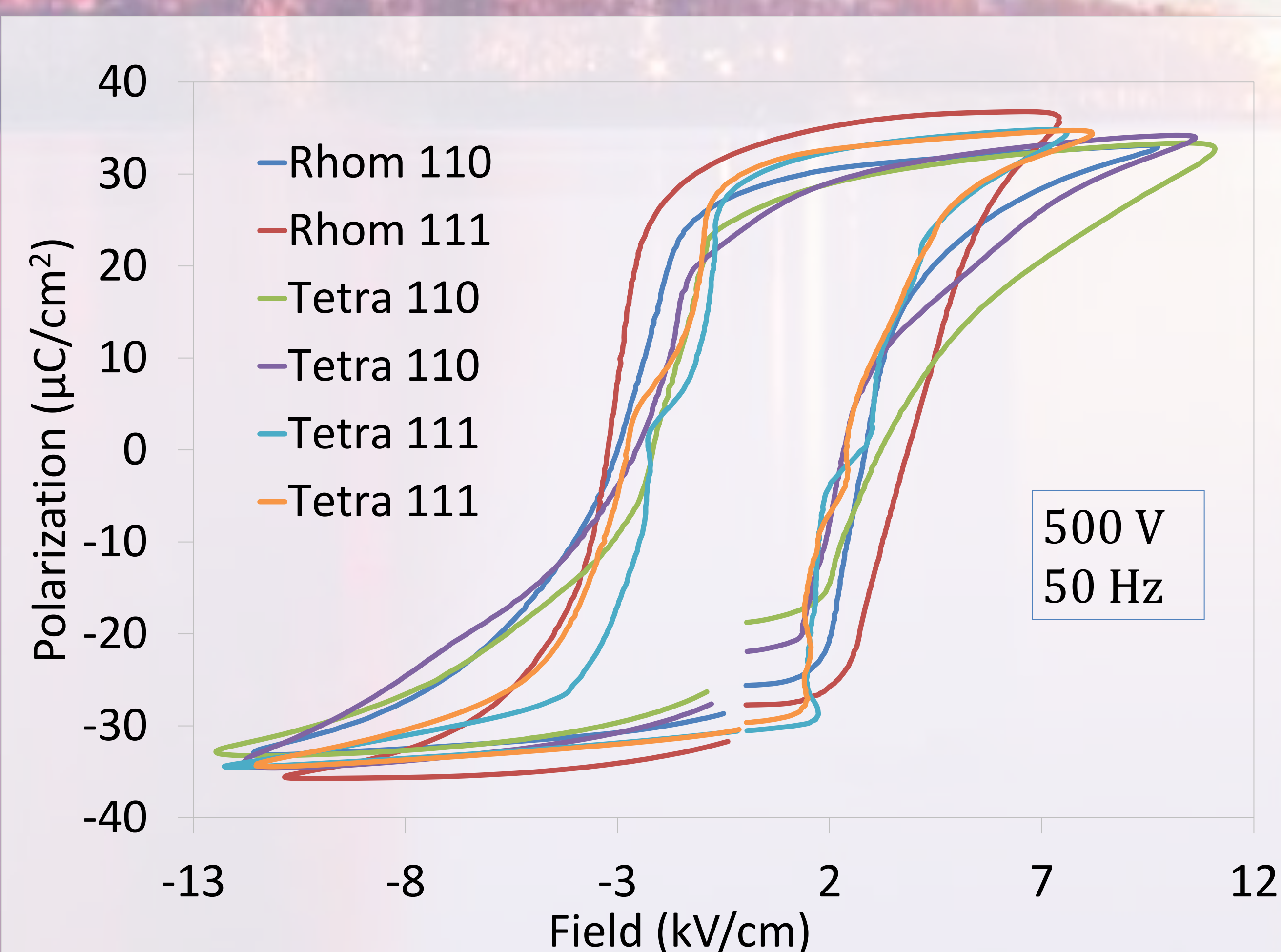
- [001]-poled lead titanate-based relaxor-ferroelectric single crystals were chosen for the study because:
 - higher piezoelectric response^{5,6}
 - lower surface to volume ratio
 - lack of grain boundaries

Low Field Dielectric Response

	Orientation	Capacitance (nF)	Dissipation factor (%)	Permittivity
Tetragonal 35-36% PT	001	1.88	0.86	2912
	001	1.73	1.2	2671
	110	2.42	0.7	3724
	110	2.43	0.7	3739
	111	2.43	0.6	3739
	111	1.92	0.6	2954
Rhomboidal 28% PT	001	1.24	0.4	1921
	001	1.27	0.4	1944
	110	1.37	1	2069
	110	1.34	1	2064
	111	1.3	0.8	2002
	111	1.3	0.6	2000

- Low field dielectric permittivity has been characterized prior to radiation.

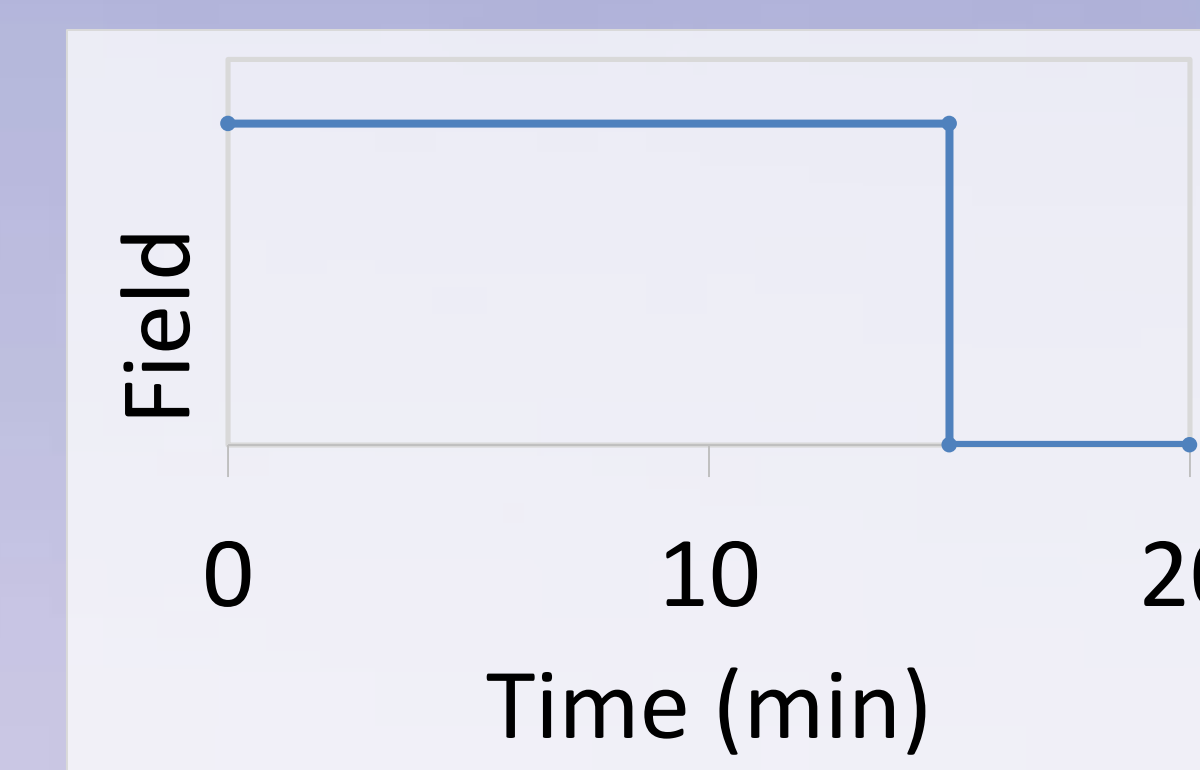
High-Field Dielectric Response



- The coercive field and voltage found was $E_c = 2.78$ KV/cm, and $V_c = 139$ V respectively.

Poling Study

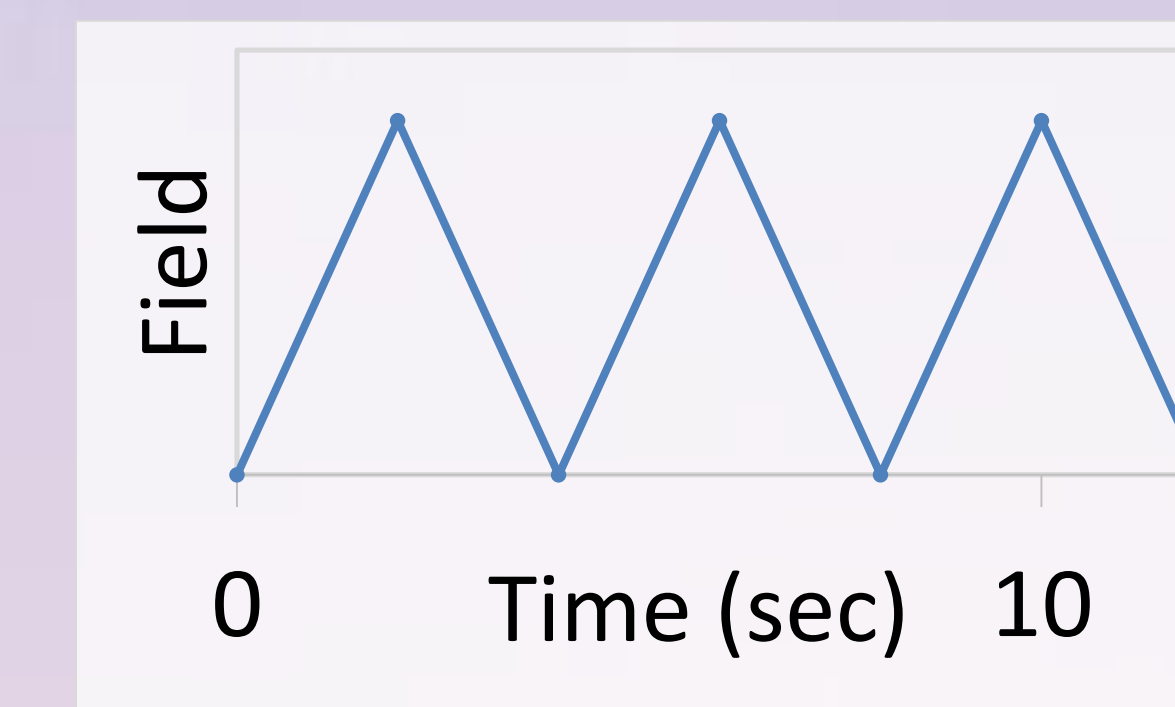
DC Field Poling: applies a large bias for a long duration allowing the defects to realign themselves with the domain walls.



V _c	(V)	(KV/cm)
1xV _c	100	2
2xV _c	250	5
3xV _c	400	8
4xV _c	500	10

- Temperatures: 25°C & 125°C. Duration: 15 min.
- Cool below transition temperature with the stable field.
- Measure $d_{33,f}$ 1min, 60min, 120 min after each run.

Unipolar Fast Pulsed Poling: applies large bias pulses for a short duration which dislodges the domain walls from the pinning centers.



- Duration: 10sec
- Frequency 55Hz
- Voltages: 150V to 500 V at steps of 50 V.
- Measure d_{33}

- Raise temperature to 175°C to disorient dipoles.
- Radiation can disorder current pinning sites and create new ones, limiting domain wall movement.
- The best method is expected to be pulsed poling because it reduces the correlation between the location of pinning sites and domain walls.

Future Work

- Optimize the capacitance-voltage, dielectric and piezoelectric responses as a function of the poling profile.
- Irradiate samples with X-rays and protons up to 5 Mrads.
- Repeat all measurements after irradiation to avoid recovery from the treatment.

References

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